Issue	Classification

Application/Control No.	Applicant(s)/Patent under Reexamination							
10/018,364	SAUTTER ET AL.							
Examiner	Art Unit							
Jean W. Désir	2614							

ISSUE CLASSIFICATION													
	ORIGINAL	CROSS REFERENCE(S)											
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)										
348	725	348	553	553	516								
INTERNATIO	NAL CLASSIFICATION	457	ろりよ	135									
HOH	N 5744	373	349										
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Jean W. Desi + 10/1/04 SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 2600							Total Claims Allowed: 20						
B(Legal Instruments Examiner) (Date) (Primary Examiner) (Date)							O. Print C	G. laim(s)	O.G. Print Fig.				

										☐ CPA			☐ T.D.			☐ R.1.47		
Final	Original	Final	Original		Final	Original		Final	Original		Final	Original		Final	Original		Final	Original
	1	13	31			61			91			121			151			181
	1	14	- 32			62			92			122			152			182
	3	15	• 33			63	,		93			123			153			183
	4	16	34			64			94			124			154			184
	\$	17	35			65			95	!		125			155			185
	6	18	36			66			96			126			156			186
	-	19	37			67			97			127			157			187
	-8	20	(38)			68			98			128			158			188
	9		39			69		_	99			129			159			189
	10		40			70			100			130			160			190
	11		41		_	71			101			131			161			191
	12		42			72			102			132			162			192
	13		43			73			103			133			163			193
	14		44			74			104			134			164			194
	15		45			75			105			135			165			195
	16		46			76			106			136			166			196
	17		47	1		77			107			137			167			197
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	19		49			79			109			139	Į		169	, [199
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	24		_54	ļ.		84	ļ		114			144	ļ		174			204
7	25		55	ļ		85	ļ		115			145	Į		175	[205
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7	27		57			87			117			147			177	Ţ		207
U	28		58			88	ļ		118			148	Į		178	[208
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42	30		60	1		90			120			150			180			210